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Class	Subclass
ISSUE	

PATENT NUMBER

U.S. UTILITY Patent Application

745 O.I.P.E. SCANNED *[Signature]* O.A. *UR*

PATENT DATE

APPLICATION NO. 09/904425	CONT/PRIOR F	CLASS 979 33	SUBCLASS 553	ART UNIT 2856 2857	EXAMINER BENNETT
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APPLICANTS
Cindy Kohanek
Gary Babb

Linearity measuring apparatus for wafer orientation flat

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
INTERNATIONAL CLASSIFICATION							
G01B	5/20						

☐ Continued on Issue Slip Inside File Jacket

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	(Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
	(Primary Examiner) (Date)			ISSUE FEE Amount Due Date Paid	
	(Legal Instruments Examiner) (Date)			ISSUE BATCH NUMBER	

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